

RELIABILITY REPORT



RELIABILITY DATA
LT1015 / LT1016 / LT1116 / LTX016 / LT6100

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF FAILURES ⁽²⁾
CERDIP	959	8503	0134	2,544.24	0
FLATPAK/LCC	47	9412	9412	48.96	0
HERMETIC	388	8601	9448	1,052.84	0
PLASTIC DIP	5,880	8503	9820	12,747.21	0
SOIC/SOT/MSOP	77	0533	0533	77.00	0
	7,351			16,470.25	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	2,867	8503	9848	479.67	0
SOIC/SOT/MSOP	6,090	8935	0352	669.50	0
	8,957			1,149.17	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	517	8503	9904	329.35	0
FLATPAK/LCC	72	9310	0044	7.20	0
HERMETIC	87	8546	9249	8.70	0
PLASTIC DIP	1,101	8503	9918	463.31	0
SOIC/SOT/MSOP	1,129	9045	0352	162.00	0
	2,906			970.56	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	328	8730	9904	342.49	0
FLATPAK/LCC	72	9310	0044	1.08	0
HERMETIC	50	8546	9249	0.75	0
PLASTIC DIP	719	8503	9848	460.53	0
SOIC/SOT/MSOP	938	9045	0352	132.30	0
	2,107			937.15	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 0.11 FITS

(3) Mean Time Between Failures in Years = 1,037,065

Note: 1 FIT = 1 Failure in One Billion Hours.